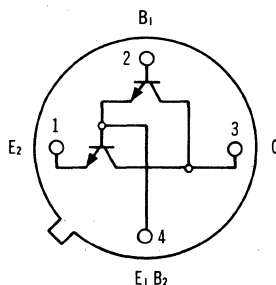


2N998 (SILICON)



CASE 20(8)
(TO-72)

Darlington amplifier containing two NPN silicon annular transistors is designed for applications requiring very high-gain, low-noise, and high-input impedance.



MAXIMUM RATINGS

Rating	Symbol	2N998	Unit
Collector-Emitter Voltage	V_{CEO}	60	Vdc
Collector-Base Voltage	V_{CB}	100	Vdc
Emitter-Base Voltage	V_{EB}	15	Vdc
Collector Current	I_C	500	mAdc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	0.5 2.86	Watt mW/ $^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	1.8 10.3	Watts mW/ $^\circ\text{C}$
Operating Junction Temperature	T_J	+200	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-65 to +200	$^\circ\text{C}$

2N998 (continued)

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Sustaining Voltage ⁽¹⁾ ($I_C = 30\text{ mAdc}$, $I_B = 0$)	$BV_{CEO(sus)}$	60	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 100\ \mu\text{Adc}$, $I_E = 0$)	BV_{CBO}	100	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100\ \mu\text{Adc}$, $I_C = 0$)	BV_{EBO}	15	—	Vdc
Collector Cutoff Current ($V_{CB} = 90\text{ Vdc}$, $I_E = 0$) ($V_{CB} = 90\text{ Vdc}$, $I_E = 0$, $T_A = 150^\circ\text{C}$)	I_{CBO}	—	0.01 15	μAdc
Emitter Cutoff Current ($V_{BE} = 10\text{ Vdc}$, $I_C = 0$)	I_{EBO}	—	0.01	μAdc

ON CHARACTERISTICS

DC Current Gain ⁽¹⁾ ($I_C = 1\text{ mAdc}$, $V_{CE} = 5\text{ Vdc}$) ($I_C = 10\text{ mAdc}$, $V_{CE} = 5\text{ Vdc}$) ($I_C = 100\text{ mAdc}$, $V_{CE} = 5\text{ Vdc}$) ($I_C = 10\text{ mAdc}$, $V_{CE} = 5\text{ Vdc}$, measured across each transistor within the device)	h_{FE}	800 1,600 2,000 25	— 8,000 — —	—
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DYNAMIC CHARACTERISTICS

Output Capacitance ($V_{CB} = 10\text{ Vdc}$, $I_E = 0$, $f = 140\text{ kHz}$)	C_{ob}	—	30	pF
Input Capacitance ($V_{BE} = 0.5\text{ Vdc}$, $I_C = 0$, $f = 140\text{ kHz}$)	C_{ib}	—	50	pF
Small-Signal Current Gain ($I_C = 1\text{ mAdc}$, $V_{CE} = 5\text{ Vdc}$, $f = 1\text{ kHz}$)	h_{fe}	1,000	—	—
Noise Figure** ($I_C = 0.1\text{ mAdc}$, $V_{CE} = 10\text{ Vdc}$, $R_S = 5\text{ kohms}$, $f = 1\text{ kHz}$, Bandwidth = 200 Hz)	NF**	—	6.0	dB

⁽¹⁾ Pulse Test: Pulse Width = 300 μs , Duty Cycle = 1%

**Measured with constant current supply of 20 μAdc connected to the emitter of the input transistor. (See Figure 1)

FIGURE 1 — NOISE-FIGURE TEST CIRCUIT

